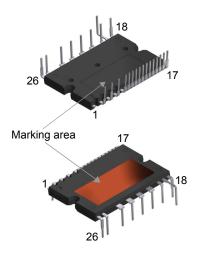


STGIB8CH60TS-E

Datasheet

SLLIMM - 2nd series IPM, 3-phase inverter, 12 A, 600 V, short-circuit rugged IGBT



SDIP2B-26L type E



Product status link STGIB8CH60TS-E

Product summary			
Order code	STGIB8CH60TS-E		
Marking	GIB8CH60TS-E		
Package	SDIP2B-26L type E		
Packing	Tube		

Features

- IPM 12 A, 600 V, 3-phase IGBT inverter bridge including 2 control ICs for gate driving and freewheeling diodes
- 3.3 V, 5 V TTL/CMOS inputs with hysteresis
- Internal bootstrap diode
- Undervoltage lockout of gate drivers
- Smart shutdown function
- Short-circuit protection
- Shutdown input/fault output
- Separate open emitter outputs
- Built-in temperature sensor
- Comparator for fault protection
- Short-circuit rugged TFS IGBTs
- Very fast, soft recovery diodes
- 85 kΩ NTC, UL 1434, CA 4 recognized
- Fully isolated package
- Isolation rating of 1600 Vrms/min
- UL recognition: UL 1557, file E81734

Applications

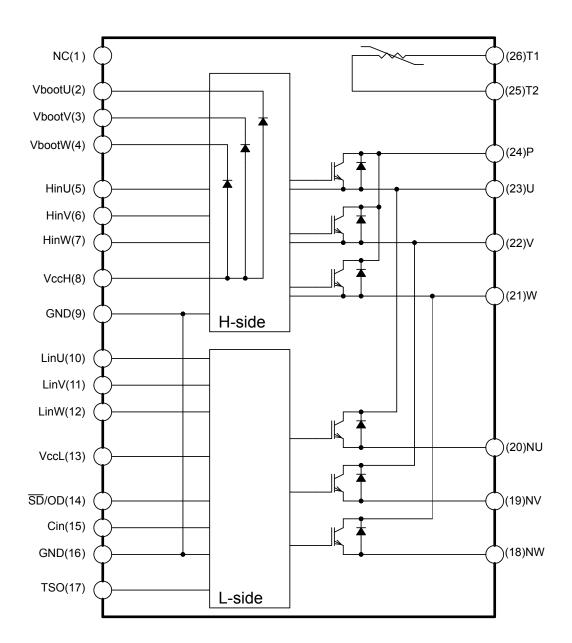
- 3-phase inverters for motor drives
- Washing machines
- Dryer
- Industrial fans
- Pumps

Description

This second series of SLLIMM (small low-loss intelligent molded module) provides a compact, high-performance AC motor drive in a simple, rugged design. It combines new ST proprietary control ICs (one LS and one HS driver) with an improved short-circuit rugged trench gate field-stop (TFS) IGBT, making it ideal for motor drives operating up to 20 kHz in hard-switching circuitries.

1 Internal schematic and pin description





GIPG120520140842FSR

Pin	Symbol	Description
1	NC	-
2	VBOOTu	Bootstrap voltage for U phase
3	VBOOTv	Bootstrap voltage for V phase
4	VBOOTw	Bootstrap voltage for W phase
5	HINu	High-side logic input for U phase
6	HINv	High-side logic input for V phase
7	HINw	High-side logic input for W phase
8	VCCH	High-side low voltage power supply
9	GND	Ground
10	LINu	Low-side logic input for U phase
11	LINv	Low-side logic input for V phase
12	LINw	Low-side logic input for W phase
13	VCCL	Low-side low voltage power supply
14	<u>SD</u> /OD	Shutdown logic input (active low) / open-drain (comparator output)
15	CIN	Comparator input
16	GND	Ground
17	TSO	Temperature sensor output
18	NW	Negative DC input for W phase
19	NV	Negative DC input for V phase
20	NU	Negative DC input for U phase
21	W	W phase output
22	V	V phase output
23	U	U phase output
24	Р	Positive DC input
25	T2	NTC thermistor terminal 2
26	T1	NTC thermistor terminal 1

Table 1. Pin description

2 Absolute maximum ratings

T_J = 25 $^\circ C$ unless otherwise noted.

Symbol	Parameter	Value	Unit
V _{PN}	Supply voltage among P -N _U , -N _V , -N _W	450	V
V _{PN(surge)}	Supply voltage surge among P -N _U , -N _V , -N _W	500	V
V _{CES}	Collector-emitter voltage each IGBT	600	V
+	Continuous collector current each IGBT (T _C = 25 $^{\circ}$ C)	12	Α
± I _C	Continuous collector current each IGBT (T _C = 80 $^{\circ}$ C)	8	
± I _{CP}	Peak collector current each IGBT (less than 1 ms)	24	А
P _{TOT}	Total power dissipation at T_C = 25 °C each IGBT	50	W
t _{scw}	Short-circuit withstand time, V _{CE} = 300 V, T _J = 125 °C, V _{CC} = V _{boot} = 15 V, V _{IN} = 0 to 5 V	5	μs

Table 2. Inverter part

Table 3. Control part

Symbol	Parameter	Min.	Max.	Unit
V _{CC}	Supply voltage between V_{CCH} -GND, V_{CCL} -GND	-0.3	20	V
V _{BOOT}	Bootstrap voltage	-0.3	619	V
V _{OUT}	Output voltage among U, V, W and GND	V _{BOOT} - 21	V _{BOOT} + 0.3	V
V _{CIN}	Comparator input voltage	-0.3	20	V
V _{IN}	Logic input voltage applied among HINx, LINx and GND	-0.3	15	V
V _{SD/OD}	Open-drain voltage	-0.3	7	V
I _{SD/OD}	Open-drain sink current		10	mA
V _{TSO}	Temperature sensor output voltage	-0.3	5.5	V
I _{TSO}	Temperature sensor output current		7	mA

Table 4. Total system

Symbol	Parameter	Value	Unit
V _{ISO}	Isolation withstand voltage applied between each pin and heat sink plate (AC voltage, t = 60 s)	1600	Vrms
TJ	Power chip operating junction temperature range	-40 to 175	°C
T _C	Module operation case temperature range	-40 to 125	°C



2.1 Thermal data

Table 5. Thermal data

Symbol	Parameter	Value	Unit
R _{thJC}	Thermal resistance, junction-to-case, single IGBT	3	°C/W
' `tnJC	Thermal resistance, junction-to-case, single diode	6	0/00

3 Electrical characteristics

 $T_{\rm J}$ = 25 °C unless otherwise specified.

3.1 Inverter part

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{CES}	Collector cut-off current	V_{CE} = 600 V, V_{CC} = V_{boot} = 15 V	-		100	μA
V _{CE(sat)} Collector-emitter saturation voltage	Collector-emitter saturation	$V_{CC} = V_{boot} = 15 \text{ V}, V_{IN}^{(1)} = 0 \text{ to } 5 \text{ V},$ $I_C = 8 \text{ A}$	-	1.68	2.18	V
	$V_{CC} = V_{boot} = 15 \text{ V}, V_{IN}^{(1)} = 0 \text{ to } 5 \text{ V},$ $I_C = 12 \text{ A}$	-	1.91		v	
V _F	Diode forward voltage	V _{IN} = 0 V, I _C = 8 A	-	1.55	2.10	V
		V _{IN} = 0 V, I _C = 12 A	-	1.70		V

Table 6. Static

1. Applied among HINx, LINx and GND for x = U, V, W.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{on} ⁽¹⁾	Turn-on time		-	280	-	
t _{c(on)} ⁽¹⁾	Crossover time on		-	142	-	
t _{off} ⁽¹⁾	Turn-off time		-	400	-	ns
$t_{c(off)}^{(1)}$	Crossover time off	V_{DD} = 300 V, V_{CC} = V_{boot} = 15 V,	-	85	-	
t _{rr}	Reverse recovery time	$V_{IN}^{(2)} = 0$ to 5 V, $I_C = 8$ A	-	215	-	
Eon	Turn-on switching energy		-	201	-	
E _{off}	Turn-off switching energy		-	102	-	μJ
Err	Reverse recovery energy		-	8.1	-	
t _{on} ⁽¹⁾	Turn-on time		-	300	-	
t _{c(on)} ⁽¹⁾	Crossover time on		-	175	-	
$t_{\text{off}}^{(1)}$	Turn-off time		-	380	-	ns
$t_{c(off)}^{(1)}$	Crossover time off	V_{DD} = 300 V, V_{CC} = V_{boot} = 15 V,	-	85	-	
t _{rr}	Reverse recovery time	$V_{IN}^{(2)}$ = 0 to 5 V, I _C = 12 A	-	220	-	
Eon	Turn-on switching energy		-	340	-	
E _{off}	Turn-off switching energy		-	160	-	μJ
Err	Reverse recovery energy		-	10.2	-	

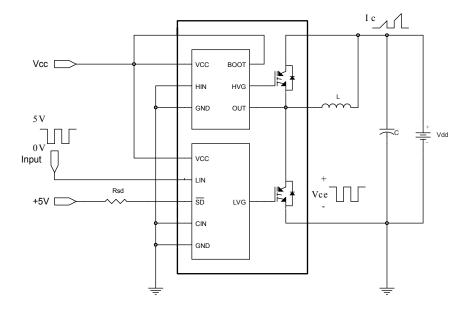
Table 7. Inductive load switching time and energy

 t_{on} and t_{off} include the propagation delay times of the internal drive. t_{C(on)} and t_{C(off)} are the switching times of the IGBT itself under the internally given gate driving conditions.

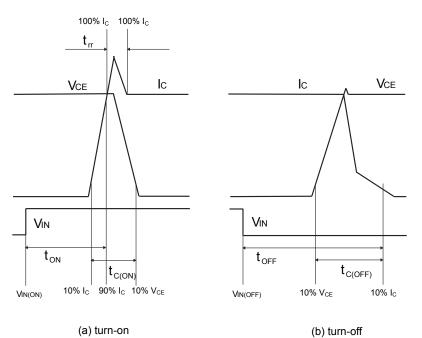
2. Applied among HINx, LINx and GND for x = U, V, W.











AM09223V1

3.2 Control/protection parts

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Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
V _{il}	Low logic level voltage				0.8	V
V _{ih}	High logic level voltage		2			V
l _{INh}	IN logic "1" input bias current	IN _x = 15 V	80	150	200	μA
I _{INI}	IN logic "0" input bias current	IN _x = 0 V			1	μA
		High-side			1	
V _{CC_hys}	V _{CC} UV hysteresis		1.2	1.4	1.7	V
V _{CCH_th(on)}	V _{CCH} UV turn-on threshold		11	11.5	12	V
V _{CCH_th(off)}	V _{CCH} UV turn-off threshold		9.6	10.1	10.6	V
V _{BS_hys}	V _{BS} UV hysteresis		0.5	1	1.6	V
V _{BS_th(on)}	V _{BS} UV turn-on threshold		10.1	11	11.9	V
V _{BS_th(off)}	V _{BS} UV turn-off threshold		9.1	10	10.9	V
I _{QBSU}	Under voltage V _{BS} quiescent current	V _{BS} = 9 V, HINx ⁽¹⁾ = 5 V		55	75	μA
I _{QBS}	V _{BS} quiescent current	V _{CC} = 15 V, HINx ⁽¹⁾ = 5 V		125	170	μA
I _{qccu}	Under voltage quiescent supply current	V _{CC} = 9 V, HINx ⁽¹⁾ = 0 V		190	250	μA
I _{qcc}	Quiescent current	V _{CC} = 15 V, HINx ⁽¹⁾ = 0 V		560	730	μA
R _{DS(on)}	BS driver ON resistance			150		Ω
		Low-side			1	
V _{CC_hys}	V _{CC} UV hysteresis		1.1	1.4	1.6	V
V _{CCL_th(on)}	V _{CCL} UV turn-on threshold		10.4	11.6	12.4	V
V _{CCL_th(off)}	V _{CCL} UV turn-off threshold		9.0	10.3	11	V
		V _{CC} = 10 V,				
I _{qccu}	Under voltage quiescent supply current	$\overline{\text{SD}}$ pulled to 5 V through R _{SD} = 10 k Ω ,		600	800	μA
		$CIN = LINx^{(1)} = 0 V$				
I _{qcc}	Quiescent current	$V_{CC} = 15 \text{ V}, \overline{\text{SD}} = 5 \text{ V},$		700	900	μA
·400		$CIN = LINx^{(1)} = 0 V$				Pri 1
V _{SSD}	Smart SD unlatch threshold		0.5	0.6	0.75	V
I _{SDh}	SD logic "1" input bias current	<u>SD</u> = 5 V	25	50	70	μA
I _{SDI}	SD logic "0" input bias current	$\overline{SD} = 0 V$			1	μA

Table 8. High- and low-side drivers

1. Applied between HINx, LINx and GND for x = U, V, W.

Table 9.	Temperature	sensor	output
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Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
V _{TSO}	Temperature sensor output voltage	T _J = 25 °C	0.974	1.16	1.345	V
I _{TSO_SNK}	Temperature sensor sink current capability			0.1		mA
I _{TSO_SRC}	Temperature sensor source current capability		4			mA

Table 10. Sense comparator (V_{CC} = 15 V, unless otherwise is specified)

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
I _{CIN}	CIN input bias current	V _{CIN} = 1 V	-0.2		0.2	μA
V _{ref}	Internal reference voltage		460	510	560	mV
V _{OD}	Open-drain low level output voltage	I _{od} = 5 mA			500	mV
t _{CIN_SD}	C _{IN} comparator delay to SD	\overline{SD} pulled to 5 V through R _{SD} = 10 kΩ; measured applying a voltage step 0-1 V to pin CIN; 50% CIN to 90% \overline{SD}	240	320	410	ns
SR _{SD}	SD fall slew rate	\overline{SD} pulled to 5 V through R _{SD} = 10 kΩ; C _L = 1 nF through \overline{SD} and ground; 90% \overline{SD} to 10% \overline{SD}		25		V/µs

The comparator stays enabled even if V_{CC} is in the UVLO condition but higher than 4 V.

4 Fault management

The device integrates an open-drain output connected to the \overline{SD} pin. As soon as a fault occurs, the open-drain is activated and the LVGx outputs are forced low. Two types of fault can be identified:

- Overcurrent (OC) sensed by the internal comparator (see more detail in Section 4.1 Smart shutdown function);
- Undervoltage on supply voltage (V_{CC})

Each fault enables the SD open drain for a different time, as described in the following table.

Symbol	Parameter	Event time ⁽¹⁾	SD open-drain enable time result ⁽¹⁾⁽²⁾
OC	Over-current event	≤ 24 µs	24 µs
	Over-current event	> 24 µs	OC time
UVLO	Under-voltage lockout event	≤ 70 µs	70 µs
		> 70 µs	
		until the VCC_LS exceeds the VCC_LS UV turn ON threshold	UVLO time

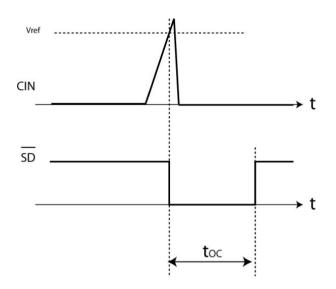
Table 11. Fault timing

1. Typical value (-40 °C \leq T_J \leq +125 °C).

2. Without contribution of the RC network on SD.

Actually, the device remains in a fault condition (\overline{SD} at low logic level and LVGx outputs disabled) for a time also depending on the RC network connected to the \overline{SD} pin. The network generates a time contribution that is added to the internal value.

Figure 4. Overcurrent timing (without contribution of the RC network on SD)



GIPG120520141638FSR



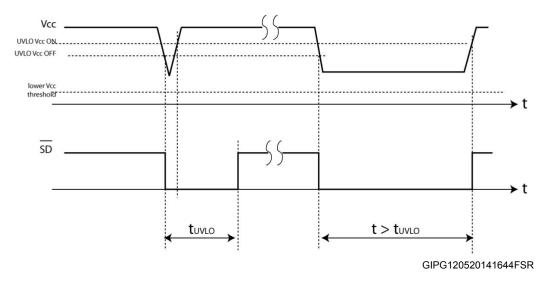
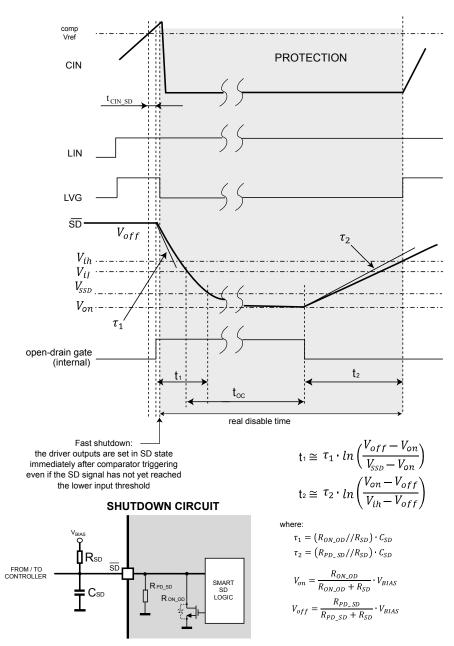


Figure 5. UVLO timing (without contribution of the RC network on $\overline{\text{SD}}$)

4.1 Smart shutdown function

The device integrates a comparator committed to the fault sensing function. The comparator input can be connected to an external shunt resistor in order to implement a simple overcurrent detection function. The output signal of the comparator is fed to an integrated MOSFET with the open drain output available on the SD input. When the comparator triggers, the device is set in shutdown state and its outputs are all set to low level.





 $R_{ON_OD} = V_{OD}/5$ mA, see Table 10. Sense comparator ($V_{CC} = 15$ V, unless otherwise is specified); R_{PD_SD} (typ.) = 5 V/I_{SDh} In common overcurrent protection designs, the comparator output is usually connected to the \overline{SD} input and an RC network is connected to this \overline{SD} line in order to provide a mono-stable circuit which implements a protection time that follows the fault condition.

As opposed to common fault detection systems, the device smart shutdown architecture allows the immediate turn-off of output gates driver in case of fault, by minimizing the propagation delay between the fault detection event and the actual switching off of the outputs. In fact, the time delay between the fault and the turning off of the outputs is no longer dependent on the RC value of the external network connected to the pin.

In the smart shutdown circuitry, the fault signal has a preferential path which directly switches off the outputs after the comparator triggering.

At the same time, the internal logic turns on the open-drain output and holds it on until the \overline{SD} voltage goes below the V_{SSD} threshold and the t_{oc} time is elapsed.

The driver outputs restart following the input pins as soon as the voltage at the SD pin reaches the higher threshold of the SD logic input.

The smart shutdown system provides the possibility to increase the time constant of the external RC network (i.e., the disable time after the fault event) up to very high values without increasing the delay time of the protection.

5 Temperature monitoring solutions

5.1 TSO output

The device integrates a temperature sensor. A voltage proportional to the die temperature is available on the TSO pin. When this function is not used, the pin can be left floating.

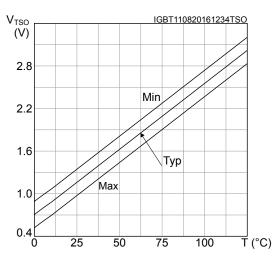


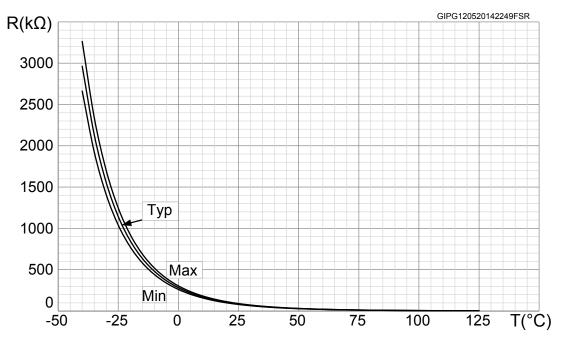
Figure 7. V_{TSO} output characteristics vs LVIC temperature

5.2 NTC thermistor

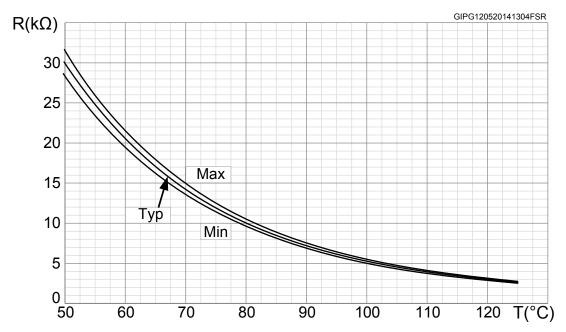
Table 12. NTC thermistor

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
R ₂₅	Resistance	T = 25 °C		85		kΩ
R ₁₂₅	Resistance	T = 125 °C		2.6		kΩ
В	B-constant	T = 25 to 100 °C		4092		К
Т	Operating temperature range		-40		125	°C









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6 Application circuit example

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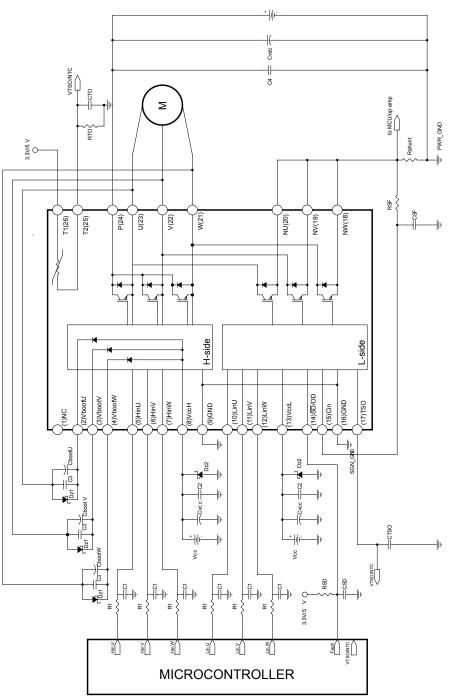


Figure 10. Application circuit example

Application designers are free to use a different scheme based on the device specifications.

6.1 Guidelines

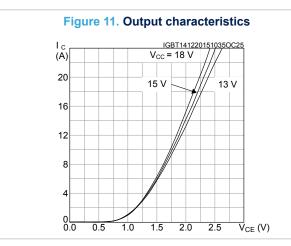
- Input signals HIN, LIN are active-high logic. A 100 kΩ (typ.) pull-down resistor is built-in for each input pin. To prevent input signal oscillations, the wiring of each input should be as short as possible and the use of RC filters (R₁, C₁) on each input signal is suggested. The filters should be with a time constant of about 100 ns and placed as close as possible to the IPM input pins.
- 2. The use of a bypass capacitor C_{VCC} (aluminum or tantalum) can reduce the transient circuit demand on the power supply. Besides, to reduce any high-frequency switching noise distributed on the power lines, a decoupling capacitor C₂ (100 to 220 nF, with low ESR and low ESL) should be placed as close as possible to each V_{cc} pin and in parallel with the bypass capacitor.
- The use of an RC filter (R_{SF}, C_{SF}) prevents protection circuit malfunctions. The time constant (R_{SF} x C_{SF}) should be set to 1 μs and the filter must be placed as close as possible to the CIN pin.
- 4. The SD is an input/output pin (open-drain type if it is used as output). It should be pulled up to a power supply (i.e., MCU bias at 3.3/5 V) by a resistor value, which can keep the I_{od} no higher than 5 mA (V_{OD} ≤ 500 mV when open-drain MOSFET is ON). The filter on SD should be sized to get a desired re-starting time after a fault event and placed as close as possible to the SD pin.
- 5. A decoupling capacitor C_{TSO} between 1 nF and 10 nF can be used to increase the noise immunity of the TSO thermal sensor; a similar decoupling capacitor C_{OT} (between 10 nF and 100 nF) can be implemented if the NTC thermistor is available and used. In both cases, their effectiveness is improved if these capacitors are placed close to the MCU.
- 6. The decoupling capacitor C₃ (100 to 220 nF with low ESR and low ESL) in parallel with each C_{boot} filters high-frequency disturbances. Both C_{boot} and C₃ (if present) should be placed as close as possible to the U,V,W and V_{boot} pins. Bootstrap negative electrodes should be connected to the U,V,W terminals directly and separated from the main output wires.
- To prevent overvoltage on the V_{CC} pin, a Zener diode (Dz1) can be used. Similarly on the V_{boot} pin, a Zener diode (Dz2) can be placed in parallel with each C_{boot}.
- The use of the decoupling capacitor C₄ (100 to 220 nF, with low ESR and low ESL) in parallel with the electrolytic capacitor C_{Vdc} prevents surge destruction. Both capacitors C₄ and C_{Vdc} should be placed as close as possible to the IPM (C₄ has priority over C_{vdc}).
- 9. By integrating an application-specific type HVIC inside the module, direct coupling to the MCU terminals without an optocoupler is possible.
- 10. Low inductance shunt resistors should be used for phase leg current sensing.
- 11. In order to avoid malfunctions, the wiring on N pins, the shunt resistor and PWR_GND should be as short as possible.
- 12. The connection of the SGN_GND to the PWR_GND at one point only (close to the shunt resistor terminal) can reduce the impact of power ground fluctuation.

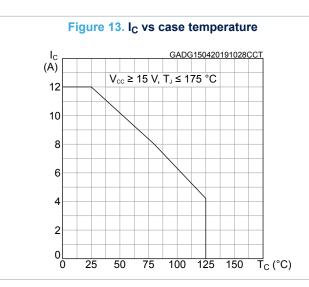
These guidelines ensure the device specifications for application designs. For further details, please refer to the relevant application note.

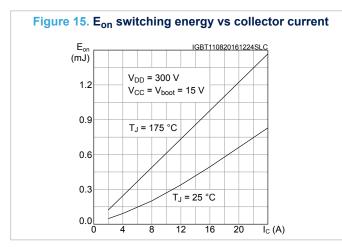
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{PN}	Supply voltage	Applied between P-Nu, N_V , N_w		300	400	V
V _{CC}	Control supply voltage	Applied between V _{CC} -GND	13.5	15	18	V
V _{BS}	High-side bias voltage	Applied between V_{BOOTi} -OUT _i for i = U, V, W	13		18	V
t _{dead}	Blanking time to prevent arm-short	For each input signal	1.0			μs
f _{PWM}	PWM input signal	-40 °C < T _C < 100 °C -40 °C < T _J < 125 °C			20	kHz
T _C	Case operation temperature				100	°C

Table 13. Recommended operating conditions









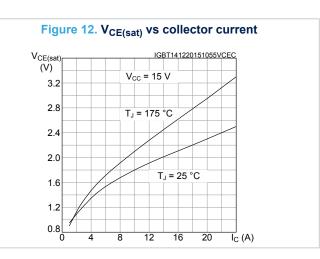


Figure 14. Diode V_{F} vs forward current

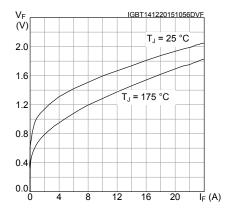


Figure 16. E_{off} switching energy vs collector current

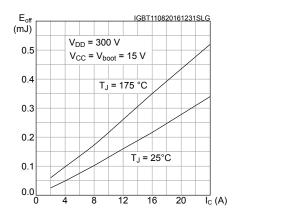
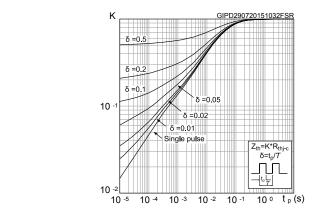


Figure 17. Thermal impedance



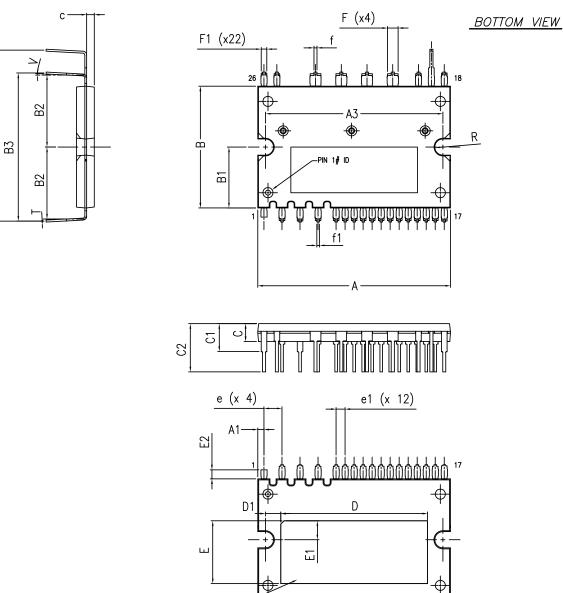
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8 Package information

B4

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

8.1 SDIP2B-26L type E package information



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e2

EXPOSED PAD-

A2

Figure 18. SDIP2B-26L type E package outline

8450802_7_type_E

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e4 (x 3)

TOP VIEW

(|)

e3 (x 4)

	Dimensions (mm)					
Ref	Min.	Тур.	Max.			
А	37.50	38.00	38.50			
A1	0.97	1.22	1.47			
A2	0.97	1.22	1.47			
A3	34.70	35.00	35.30			
С	1.45	1.50	1.55			
В	23.50	24.00	24.50			
B1		12.00				
B2	13.90	14.40	14.90			
B3	28.70	29.20	29.70			
B4	33.20	33.70	34.20			
С	3.30	3.50	3.70			
C1	5.00	5.50	6.00			
C2	9.00	9.50	10.00			
D	28.45	28.95	29.45			
D1	2.725	3.025	3.325			
е	3.356	3.556	3.756			
e1	1.578	1.778	1.978			
e2	7.42	7.62	7.82			
e3	4.88	5.08	5.28			
e4	2.34	2.54	2.74			
E	11.90	12.40	12.90			
E1	3.45	3.75	4.05			
E2		1.80				
f	0.45	0.60	0.75			
f1	0.35	0.50	0.65			
F	1.95	2.10	2.25			
F1	0.95	1.10	1.25			
R	1.55	1.575	1.60			
Т	0.375	0.40	0.425			
V	0°		5°			

Table 14. SDIP2B-26L type E package mechanical data

Revision history

Date	Revision	Changes
12-Oct-2016	1	First release.
	2	Removed maturity status indication from cover page.
		Updated features list on cover page.
16-May-2018		Updated Table 11. Fault timing.
		Updated Section 9.1 SDIP2B-26L type E package information.
		Minor text changes
	3	Updated Section 2 Absolute maximum ratings.
25-Jun-2018		Updated Section 7 Guidelines.
		Minor text changes
04 Mar 0040	4	Added Figure 13. I _C vs case temperature
21-May-2019		Minor text changes.
09-Sep-2021	5	Updated features in cover page and Table 4. Total system.

Table 15. Document revision history

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